16. TEST SETUP PHOTOGRAPHS

FCC ID: A3LSMJ737T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 72 of 74
1M1803150042-12.A3L	04/12/2018 - 04/23/2018	Portable Handset		1 age 72 0174
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04/17/2018



Figure 16-1 Test Setup for Wireless Device

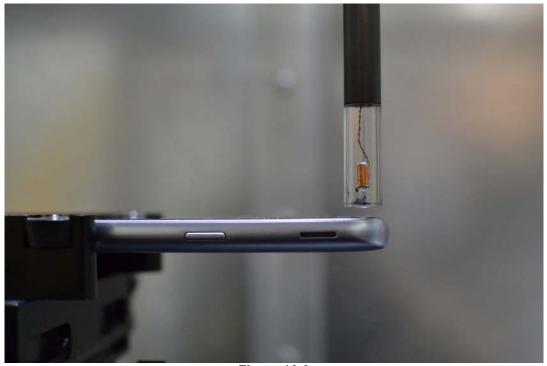


Figure 16-2 Test Setup for Wireless Device

FCC ID: A3LSMJ737T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
Filename:	Test Dates:	DUT Type:		Page 73 of 74	
1M1803150042-12.A3L	04/12/2018 - 04/23/2018	Portable Handset			
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Figure 16-3 T-Coil Scan Overlay Magnetic Field Distributions

Note: Final measurement locations are indicated by a cursor on the contour plots.

FCC ID: A3LSMJ737T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 74 of 74
1M1803150042-12.A3L	04/12/2018 - 04/23/2018	Portable Handset		rugorrorri
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